



(PATENT)

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

In re Patent Application of:  
Beaman et al.

Application No.: 10/646,673

Confirmation No.: 1020

Filed: August 21, 2003

Art Unit: 1762

For: METHODS AND APPARATUS FOR  
PROCESSING MICROFEATURE  
WORKPIECES; METHODS FOR  
CONDITIONING ALD REACTION  
CHAMBERS

Examiner: D. P. Turocy

**INFORMATION DISCLOSURE STATEMENT (IDS)**

MS Amendment  
Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Sir:

Pursuant to 37 CFR 1.56, 1.97 and 1.98, the attention of the Patent and Trademark Office is hereby directed to the references listed on the attached PTO/SB/08. It is respectfully requested that the information be expressly considered during the prosecution of this application, and that the references be made of record therein and appear among the "References Cited" on any patent to issue therefrom.

This Information Disclosure Statement, pursuant to 37 CFR 1.114(c), accompanies the Request for Continued Examination (37 CFR 1.114) submitted herewith.

In accordance with 37 CFR 1.98(a)(2)(ii), Applicants have not submitted a copy of the cited U.S. patents and U.S. patent applications. Applicants submit herewith a copy of the cited foreign patent references in accordance with 37 CFR 1.98(a)(2).

This Information Disclosure Statement is not to be construed as a representation that: (i) a search has been made; (ii) additional information material to the examination of this application does not exist; (iii) the information, protocols, results and the like reported by third parties are accurate or enabling; or (iv) the cited information is, or is considered to be, material to patentability. In addition, applicant does not admit that any enclosed item of information constitutes prior art to the subject invention and specifically reserves the right to demonstrate that any such reference is not prior art.

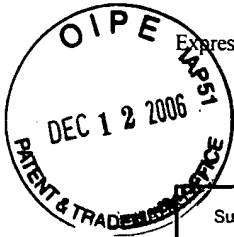
It is submitted that the Information Disclosure Statement is in compliance with 37 CFR 1.98 and the Examiner is respectfully requested to consider the listed references.

The Director is hereby authorized to charge any deficiency in the fees filed, asserted to be filed or which should have been filed herewith (or with any paper hereafter filed in this application by this firm) to our Deposit Account No. 50-0665, under Order No. 108298715US.

Dated: December 12, 2006

Respectfully submitted,

By T. R. Seeley  
Tim R. Seeley  
Registration No.: 53,575  
PERKINS COIE LLP  
P.O. Box 1247  
Seattle, Washington 98111-1247  
(206) 359-8000  
(206) 359-7198 (Fax)  
Attorney for Applicant



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Disclosure No. 03-0117.00/USPTO/SB/08a/b (07-06)  
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**INFORMATION DISCLOSURE  
STATEMENT BY APPLICANT**

(Use as many sheets as necessary)

Sheet	1	of	1	Application Number	10/646,673-Conf. #1020
				Filing Date	August 21, 2003
				First Named Inventor	Kevin L. Beaman
				Art Unit	1762
				Examiner Name	D. P. Turocy
				Attorney Docket Number	108298715US

**U.S. PATENT DOCUMENTS**

Examiner Initials*	Cite No. <sup>1</sup>	Document Number	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Number-Kind Code <sup>2</sup> (if known)			
		US-4,509,456	04-01-1985	Kleinert et al.	
		US-4,911,638	03-27-1990	Bayne et al.	
		US-5,015,330	05-14-1991	Okumura et al.	
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		US-7,086,410	08-08-2006	Chouno et al.	
		US-20060204649	09-14-2006	Beaman et al.	
		US-20060205187	09-14-2006	Zheng et al.	
		US-20060213440	09-28-2006	Zheng et al.	

**FOREIGN PATENT DOCUMENTS**

Examiner Initials*	Cite No. <sup>1</sup>	Foreign Patent Document	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T <sup>3</sup>
		Country Code <sup>3</sup> -Number <sup>4</sup> -Kind Code <sup>5</sup> (if known)				
		JP-06-201539	07-19-1994	Kitsuta, Yasuo		
		JP-64-81311-A	03/1989	NEC Corp		

\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

<sup>1</sup>Applicant's unique citation designation number (optional). <sup>2</sup>Applicant is to place a check mark here if English language Translation is attached.

Examiner Signature		Date Considered	
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